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	Christopher I Chin

Applicant(s)/Pate Reexamination	pplicant(s)/Patent under eexamination				
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updated	search	12/23/2006	cc		
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INT	INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST search	12/23/2006	СС		
STN-CAS search	12/23/2006	СС		